

G432**Adjustable Shunt Regulator****Description**

The G432 series are three-terminal adjustable precision shunt regulators with guaranteed stable temperature over the applicable extended commercial temperature range. The output voltage may be set at any level greater than 1.24V (V_{REF}) up to 20V merely by selecting two external resistors that act as a voltage divider network. These devices have a typical output impedance of 0.2Ω . Active output circuitry provides very sharp turn-on characteristics, making these devices excellent improved replacements for Zener diodes in many applications.

The precise +/- 2% reference voltage tolerance of G432 make it possible in many applications to avoid the use of a variable resistor, consequently saving cost and eliminating drift and reliability problems associated with it.

Features

*Precision reference voltage

A Rank: $1.24V \pm 0.5\%$,

B Rank: $1.24V \pm 1\%$,

C Rank: $1.24V \pm 2.0\%$

*Sink current capability: 200 mA.

*Minimum cathode current for regulation: $150 \mu A$.

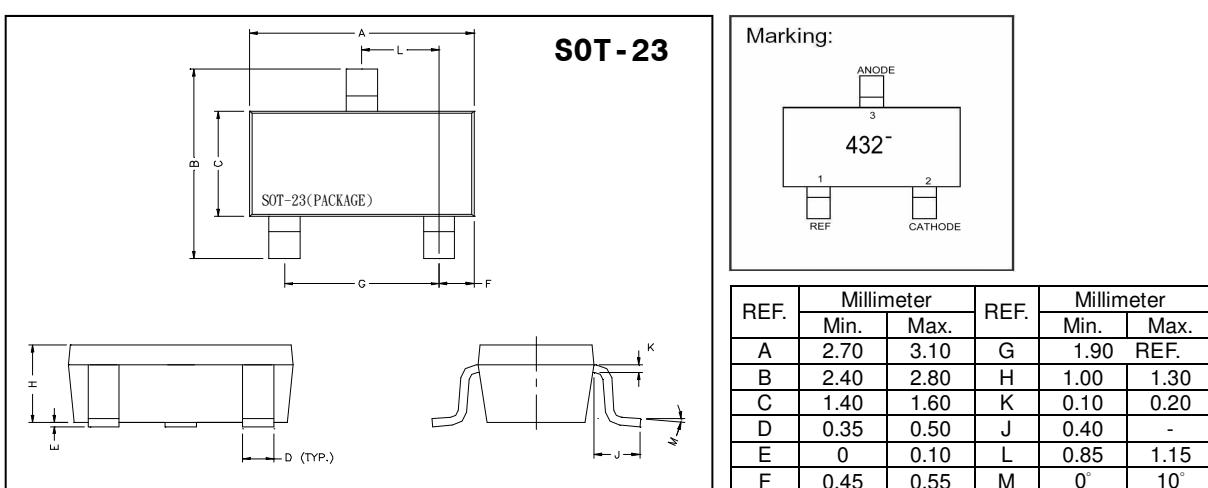
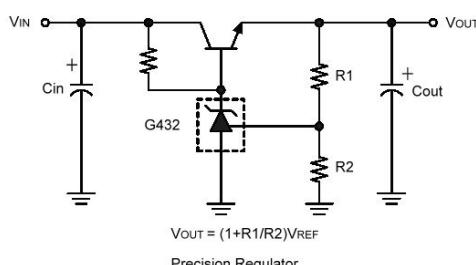
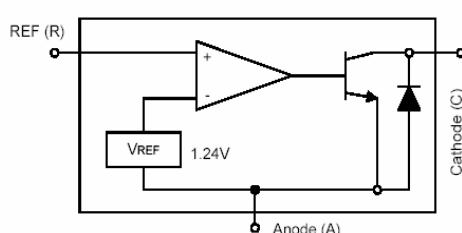
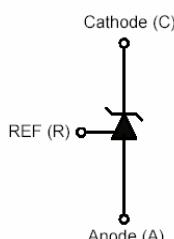
*Equivalent full-range temp coefficient: $30 \text{ ppm}/^\circ C$.

*Fast turn-on Response.

*Low dynamic output impedance: 0.2Ω .

*Programmable output voltage to 20V.

*Low output noise.

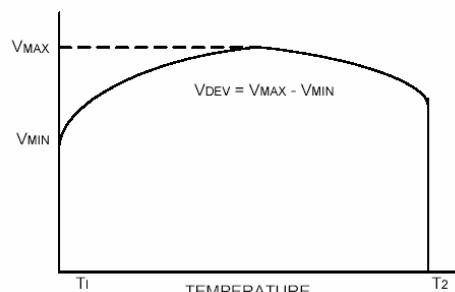
Package Dimensions**Typical Application Circuit****Block Diagram****Symbol**

Absolute Maximum Ratings at Ta = 25°C

Parameter	Symbol	Ratings	Unit
Junction Temperature	T _j	+150	°C
Storage Temperature	T _{stg}	-65 ~ +150	°C
Cathode Voltage	V _{KA}	20	V
Continuous Cathode Current	I _{KA}	-10~+250	mA
Reference Input Current Range	I _{REF}	-0.05~+10	mA
Total Power Dissipation	P _D	225	mW

Electrical Characteristics (Ta = 25°C, unless otherwise specified.)

Parameter	Symbol	Min	Typ.	Max.	Unit	Test Conditions	
Reference Voltage G432C G432B G432A	V _{REF}	1.215	1.24	1.265	V	V _{KA} = V _{REF} , I _K =10mA (Fig.1)	
		1.228	1.24	1.252			
		1.234	1.24	1.246			
Deviation of reference Input Voltage Over temperature(note1)	ΔV _{REF} /ΔT	-	3.0	20	mV	V _{KA} = V _{REF} , I _K =10mA Ta=Full range (Fig.1)	
Ratio of Change in Reference Input Voltage to the Change in Cathode Voltage	ΔV _{REF} /Δ V _{KA}	-	-1.4	-2.0	mV/V	I _K =10mA (Fig.2)	ΔV _{KA} =20V~V _{REF}
Reference Input Current	I _{REF}	-	1.4	3.5	uA	I _K =10mA,R ₁ =10KΩ,R ₂ =∞ (Fig.2)	
Deviation of reference Input Current Over Temperature Range	α I _{REF}	-	0.4	1.2	uA	I _K =10mA,R ₁ =10KΩ,R ₂ =∞ Ta=Full range(Fig.2)	
Minimum Cathode Current for Regulation	I _{KA(min)}	-	0.15	0.3	mA	V _{KA} =V _{REF} (Fig.1)	
Off-State Cathode Current	I _{KA(off)}	-	0.1	1.0	uA	V _{KA} =20V,V _{REF} =0 (Fig.3)	
Dynamic Output Impedance (note2)	Z _{KA}	-	0.2	0.5	Ω	V _{KA} =V _{REF} , I _K =1 ~100mA F≤1.0KHz(Fig.1)	



Note1. Deviation of reference input voltage, V_{DEV}, is defined as the maximum variation of the reference over the full temperature range.

The average temperature coefficient of the reference input voltage α V_{REF} is defined as:

$$|\alpha V_{REF}| = \frac{\left(\frac{V_{DEV}}{V_{REF}(25^{\circ}C)} \right) \times 10^6}{T_2 - T_1} \quad (\text{ppm}/^{\circ}\text{C})$$

Where:

T₂ – T₁ = full temperature change.

α V_{REF} can be positive or negative depending on whether the slope is positive or negative.

Note2. The dynamic output impedance, R_Z, is defined as:

$$|Z_{KA}| = \frac{\Delta V_{KA}}{\Delta I_{KA}}$$

When the device is programmed with two external resistors R1 and R2 (see figure 2.), the dynamic output impedance of the overall circuit, is defined as:

$$|Z_{KA}| = \frac{\Delta V}{\Delta i} > |Z_{KA}| \quad (1 + \frac{R1}{R2})$$

Test Circuits

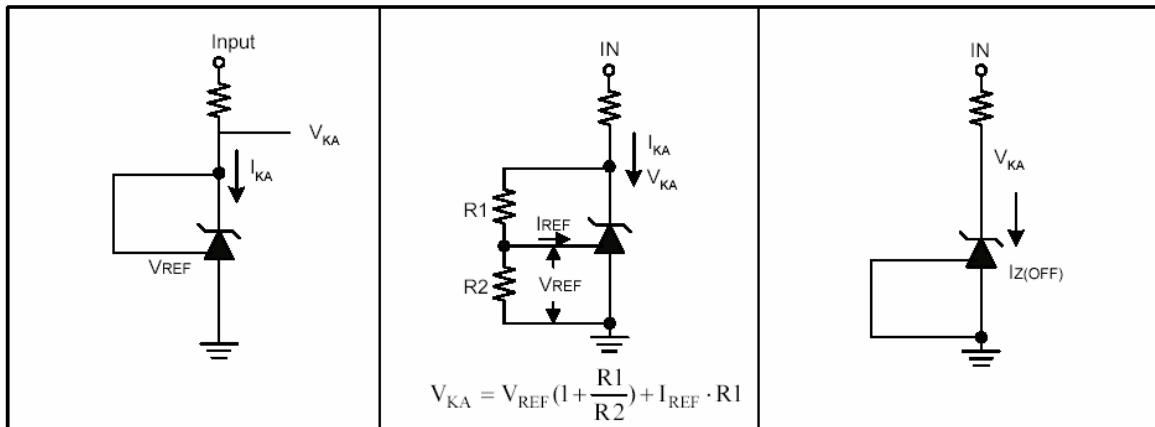
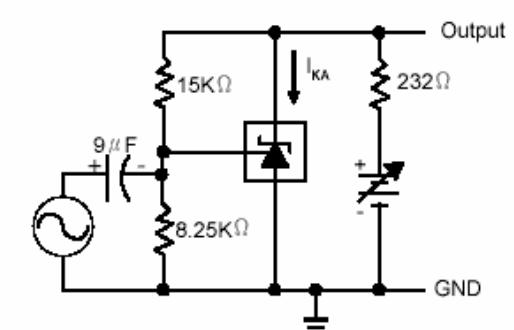
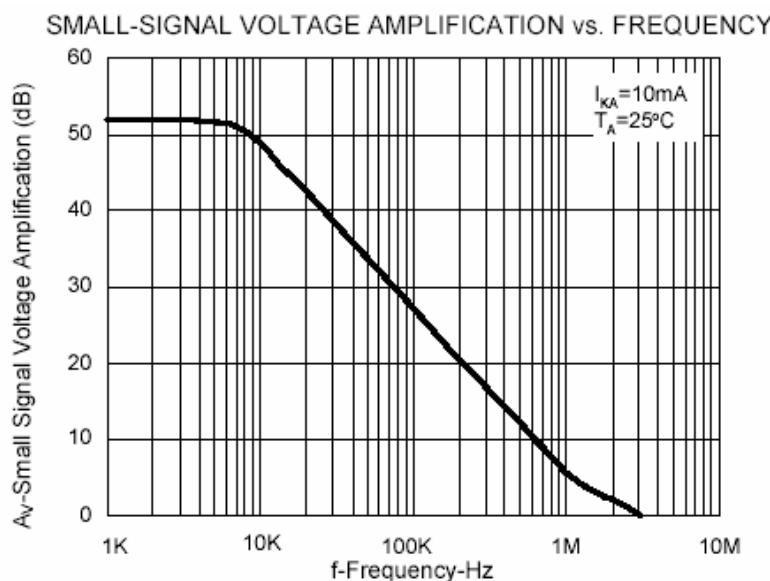


Fig1. Test Circuit for $V_{KA} = V_{REF}$

Fig2. Test circuit for $V_{KA} > V_{REF}$

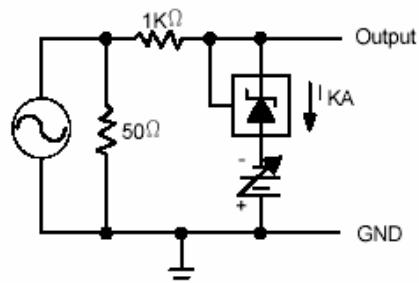
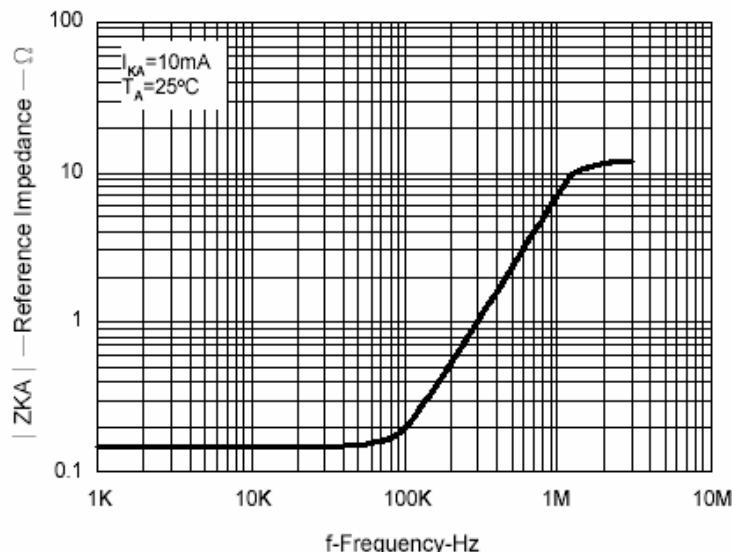
Fig3. Test Circuit for off-state Current

Typical Performance Characteristics



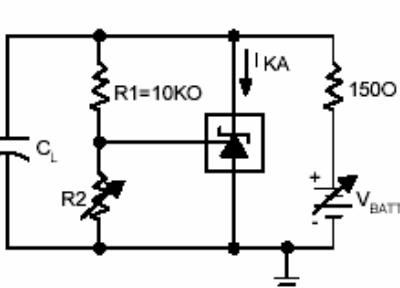
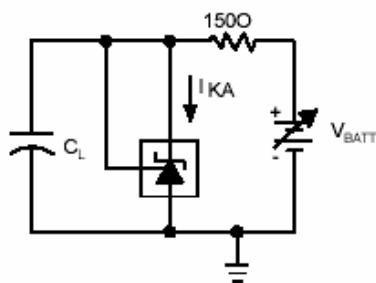
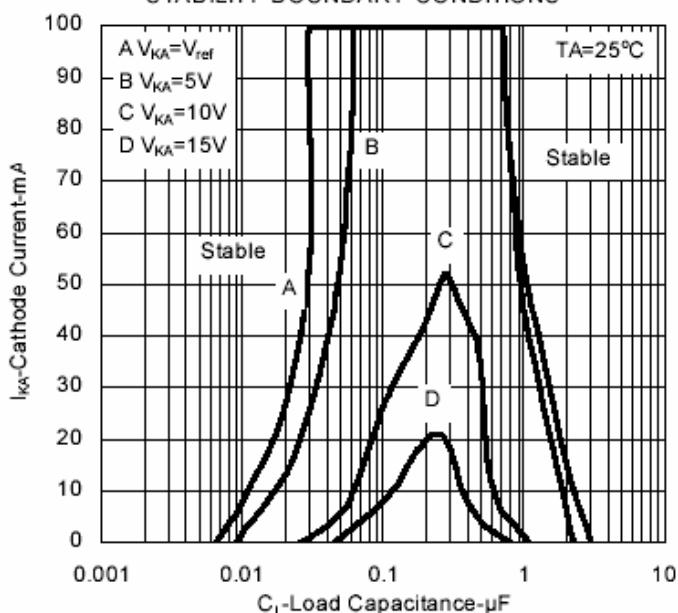
TEST CIRCUIT FOR VOLTAGE AMPLIFICATION

REFERENCE IMPEDANCE vs. FREQUENCY



TEST CIRCUIT FOR REFERENCE IMPEDANCE

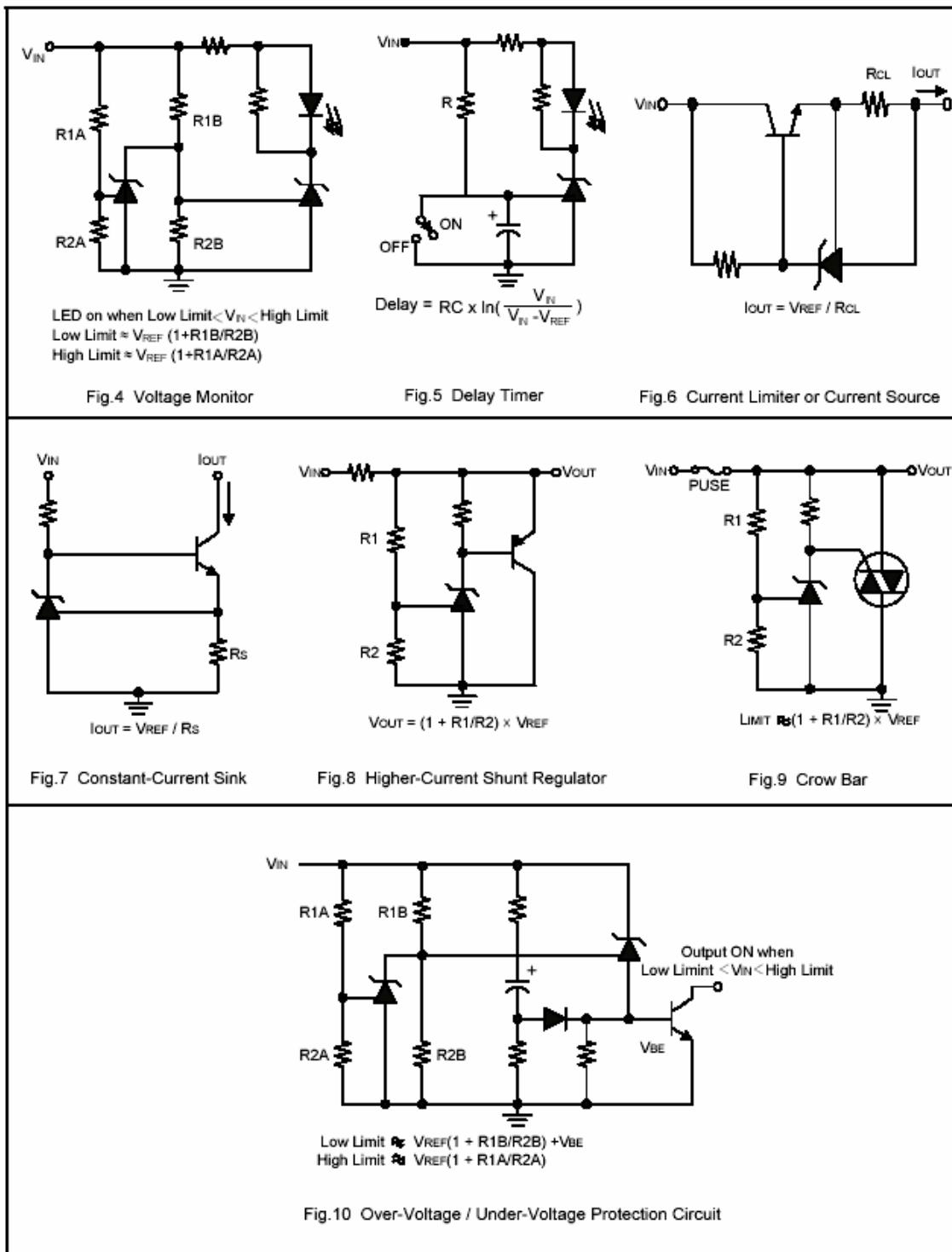
STABILITY BOUNDARY CONDITIONS[†]



TEST CIRCUIT FOR CURVE B, C, AND D

[†]The areas under the curves represent conditions that may cause the device to oscillate. For curves B, C, and D, R_2 and V_+ were adjusted to establish the initial V_{KA} and I_{KA} conditions with $C_L=0$. V_{BATT} and C_L were then adjusted to determine the ranges of stability.

Application Examples


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